

**Notice of References Cited**

Application/Control No.

09/867,124

Applicant(s)/Patent Under Reexam

Takahashi et al.

Examiner

David L. Lewis

Art Unit

2673

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**U.S. PATENT DOCUMENTS**

	<b>Document Number</b> Country Code-Number-Kind Code	<b>Date</b> MM-YYYY <sup>1</sup>	<b>Name</b>	<b>Classification</b> <sup>2</sup>	
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